

## ABSTRACT

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APPARATUS AND METHOD FOR  
TESTING SEMICONDUCTOR DEVICES

The present invention provides apparatus for supporting during a testing operation  
10 a leadframe formed with at least one row of non-singulated semiconductor devices. The  
apparatus comprises a main body and a leadframe support member, and the leadframe  
support member is formed with at least one groove for receiving semiconductor devices  
such that in use leads extending from said devices lie on a surface of said support  
member. The invention also relates to a system for transporting devices to and from a test  
15 probe head